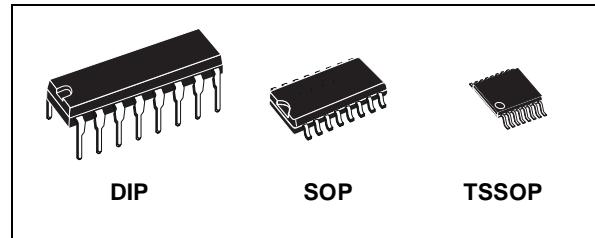


QUAD 2 CHANNEL MULTIPLEXER (3-STATE)

- HIGH SPEED: $t_{PD} = 4.5\text{ns}$ (TYP.) at $V_{CC} = 5\text{V}$
- LOW POWER DISSIPATION:
 $I_{CC} = 4\mu\text{A}$ (MAX.) at $T_A=25^\circ\text{C}$
- HIGH NOISE IMMUNITY:
 $V_{NIH} = V_{NIL} = 28 \% V_{CC}$ (MIN.)
- 50Ω TRANSMISSION LINE DRIVING CAPABILITY
- SYMMETRICAL OUTPUT IMPEDANCE:
 $|I_{OHI}| = I_{OL} = 24\text{mA}$ (MIN)
- BALANCED PROPAGATION DELAYS:
 $t_{PLH} \approx t_{PHL}$
- OPERATING VOLTAGE RANGE:
 V_{CC} (OPR) = 2V to 6V
- PIN AND FUNCTION COMPATIBLE WITH 74 SERIES 257
- IMPROVED LATCH-UP IMMUNITY

DESCRIPTION

The 74AC257 is an advanced high-speed CMOS QUAD 2-CHANNEL MULTIPLEXER (3-STATE) fabricated with sub-micron silicon gate and double-layer metal wiring C²MOS technology. It is composed of four independent 2-channel multiplexer with common SELECT and ENABLE (\overline{OE}) inputs. It is a non-inverting multiplexer. When the OE input is held HIGH, all the output become in

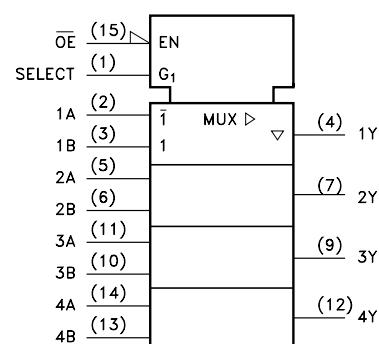
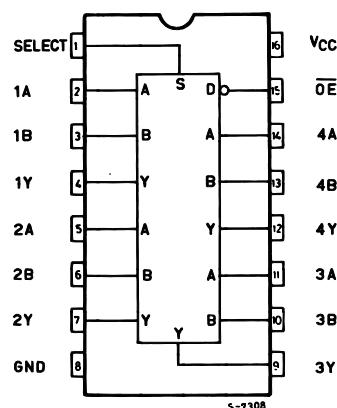


ORDER CODES

PACKAGE	TUBE	T & R
DIP	74AC257B	
SOP	74AC257M	74AC257MTR
TSSOP		74AC257TTR

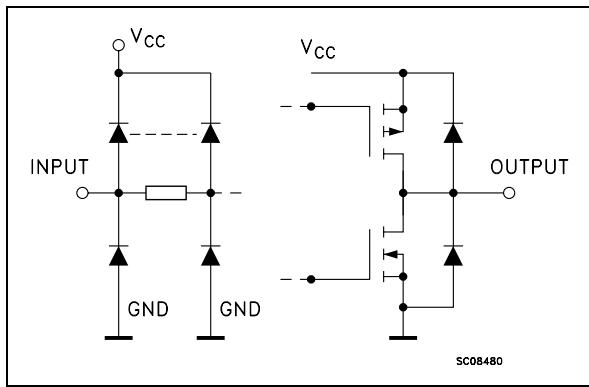
high impedance state. If SELECT input is held LOW, "A" data is selected, when SELECT input is held HIGH, "B" data is chosen. All inputs and outputs are equipped with protection circuits against static discharge, giving them 2KV ESD immunity and transient excess voltage.

PIN CONNECTION AND IEC LOGIC SYMBOLS



74AC257

INPUT AND OUTPUT EQUIVALENT CIRCUIT



PIN DESCRIPTION

PIN No	SYMBOL	NAME AND FUNCTION
1	SELECT	Common Data Select Inputs
2, 5, 11, 14	1A to 4A	Data Inputs From Source A
3, 6, 10, 13	1B to 4B	Data Inputs From Source B
4, 7, 9, 12	1Y to 4Y	Multiplexer Outputs
15	OE	3 State Output Enable Inputs (Active LOW)
8	GND	Ground (0V)
16	V _{CC}	Positive Supply Voltage

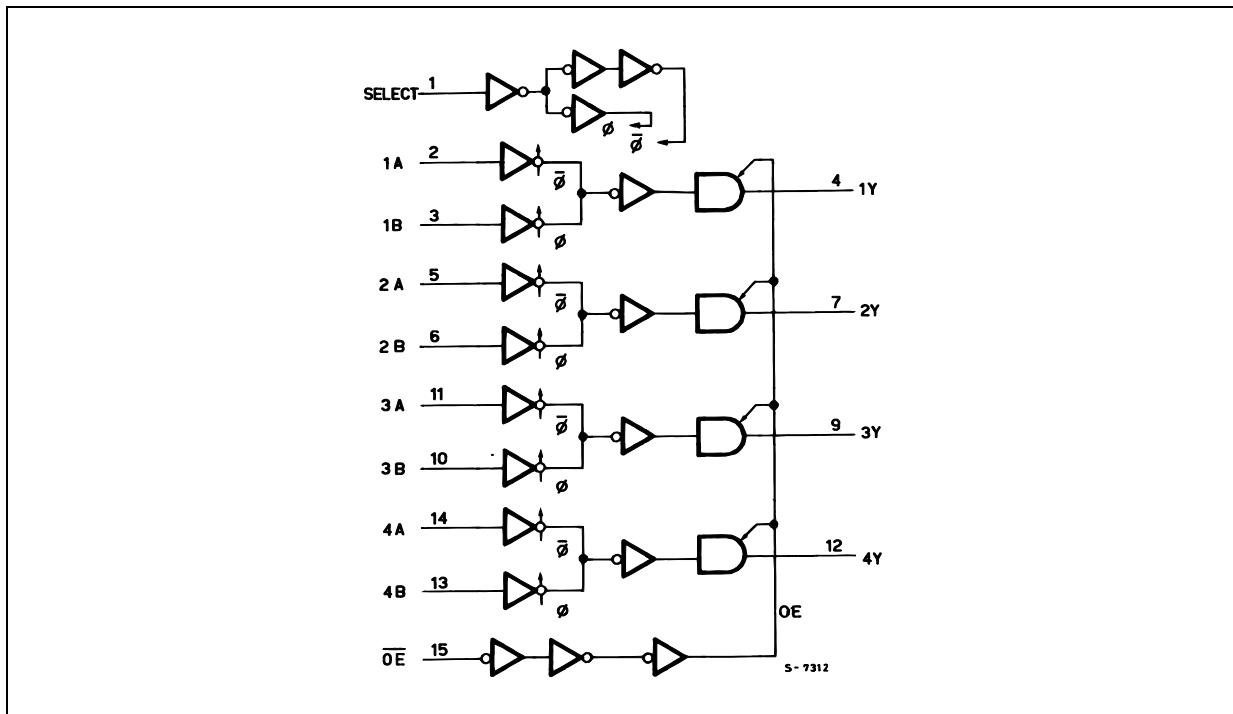
TRUTH TABLE

INPUTS				OUTPUT
\overline{OE}	SELECT	A	B	Y
H	X	X	X	L
L	L	L	X	L
L	L	H	X	H
L	H	X	L	L
L	H	X	H	H

X : Don't Care

Z : High Impedance

LOGIC DIAGRAM



This logic diagram has not been used to estimate propagation delays

ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	-0.5 to +7	V
V_I	DC Input Voltage	-0.5 to $V_{CC} + 0.5$	V
V_O	DC Output Voltage	-0.5 to $V_{CC} + 0.5$	V
I_{IK}	DC Input Diode Current	± 20	mA
I_{OK}	DC Output Diode Current	± 20	mA
I_O	DC Output Current	± 50	mA
I_{CC} or I_{GND}	DC V_{CC} or Ground Current	± 200	mA
T_{stg}	Storage Temperature	-65 to +150	°C
T_L	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these conditions is not implied.

RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value	Unit
V_{CC}	Supply Voltage	2 to 6	V
V_I	Input Voltage	0 to V_{CC}	V
V_O	Output Voltage	0 to V_{CC}	V
T_{op}	Operating Temperature	-55 to 125	°C
dt/dv	Input Rise and Fall Time $V_{CC} = 3.0, 4.5$ or $5.5V$ (note 1)	8	ns/V

1) V_{IN} from 30% to 70% of V_{CC}

DC SPECIFICATIONS

Symbol	Parameter	Test Condition		Value						Unit	
		V_{CC} (V)		$T_A = 25^\circ C$			$-40 \text{ to } 85^\circ C$		$-55 \text{ to } 125^\circ C$		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
V_{IH}	High Level Input Voltage	3.0	$V_O = 0.1 \text{ V or } V_{CC}-0.1\text{V}$	2.1	1.5		2.1		2.1		V
		4.5		3.15	2.25		3.15		3.15		
		5.5		3.85	2.75		3.85		3.85		
V_{IL}	Low Level Input Voltage	3.0	$V_O = 0.1 \text{ V or } V_{CC}-0.1\text{V}$		1.5	0.9		0.9		0.9	V
		4.5			2.25	1.35		1.35		1.35	
		5.5			2.75	1.65		1.65		1.65	
V_{OH}	High Level Output Voltage	3.0	$I_O=-50 \mu A$	2.9	2.99		2.9		2.9		V
		4.5	$I_O=-50 \mu A$	4.4	4.49		4.4		4.4		
		5.5	$I_O=-50 \mu A$	5.4	5.49		5.4		5.4		
		3.0	$I_O=-12 \text{ mA}$	2.56			2.46		2.4		
		4.5	$I_O=-24 \text{ mA}$	3.86			3.76		3.7		
		5.5	$I_O=-24 \text{ mA}$	4.86			4.76		4.7		
V_{OL}	Low Level Output Voltage	3.0	$I_O=50 \mu A$		0.002	0.1		0.1		0.1	V
		4.5	$I_O=50 \mu A$		0.001	0.1		0.1		0.1	
		5.5	$I_O=50 \mu A$		0.001	0.1		0.1		0.1	
		3.0	$I_O=12 \text{ mA}$			0.36		0.44		0.5	
		4.5	$I_O=24 \text{ mA}$			0.36		0.44		0.5	
		5.5	$I_O=24 \text{ mA}$			0.36		0.44		0.5	
I_I	Input Leakage Current	5.5	$V_I = V_{CC} \text{ or GND}$			± 0.1		± 1		± 1	μA
I_{OZ}	High Impedance Output Leakage Current	5.5	$V_I = V_{IH} \text{ or } V_{IL}$ $V_O = V_{CC} \text{ or GND}$			± 0.5		± 5		± 10	μA
I_{CC}	Quiescent Supply Current	5.5	$V_I = V_{CC} \text{ or GND}$			4		40		80	μA
I_{OLD}	Dynamic Output Current (note 1, 2)	5.5	$V_{OLD} = 1.65 \text{ V max}$					75		50	mA
			$V_{OHD} = 3.85 \text{ V min}$					-75		-50	mA

1) Maximum test duration 2ms, one output loaded at time

2) Incident wave switching is guaranteed on transmission lines with impedances as low as 50Ω

AC ELECTRICAL CHARACTERISTICS ($C_L = 50 \text{ pF}$, $R_L = 500 \Omega$, Input $t_r = t_f = 3\text{ns}$)

Symbol	Parameter	Test Condition		Value						Unit	
		V_{CC} (V)		$T_A = 25^\circ\text{C}$			$-40 \text{ to } 85^\circ\text{C}$		$-55 \text{ to } 125^\circ\text{C}$		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
t_{PLH} t_{PHL}	Propagation Delay Time A, B to Y	3.3 ^(*)		1.5	5.5	8.5	1.5	9.0	1.5	9.0	ns
		5.0 ^(**)		1.5	4.5	6.0	1.5	7.0	1.5	7.0	
t_{PLH} t_{PHL}	Propagation Delay Time SELECT to Y	3.3 ^(*)		1.5	7.0	10.5	1.5	11.5	1.5	11.5	ns
		5.0 ^(**)		1.5	5.5	7.5	1.5	8.5	1.5	8.5	
t_{PZL} t_{PZH}	Output Enable Time	3.3 ^(*)		1.5	5.5	9.0	1.5	100	1.5	100	ns
		5.0 ^(**)		1.5	4.5	7.5	1.5	8.5	1.5	8.5	
t_{PLZ} t_{PHZ}	Output Disable Time	3.3 ^(*)		1.5	7.0	10.0	1.5	11.0	1.5	13.0	ns
		5.0 ^(**)		1.5	5.5	9.0	1.5	10.0	1.5	11.0	

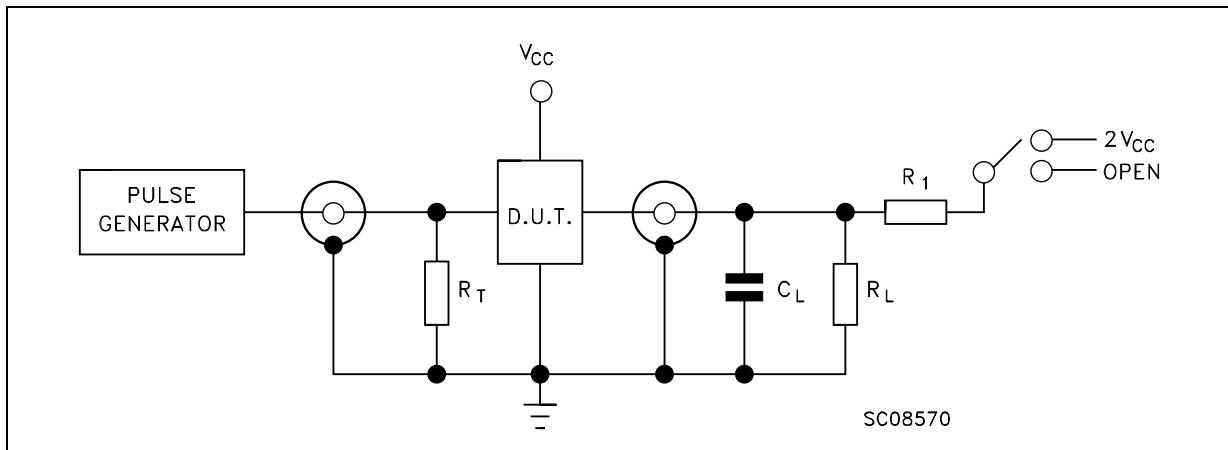
^(*) Voltage range is $3.3\text{V} \pm 0.3\text{V}$ ^(**) Voltage range is $5.0\text{V} \pm 0.5\text{V}$

CAPACITIVE CHARACTERISTICS

Symbol	Parameter	Test Condition		Value						Unit	
		V_{CC} (V)		$T_A = 25^\circ\text{C}$			$-40 \text{ to } 85^\circ\text{C}$		$-55 \text{ to } 125^\circ\text{C}$		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
C_{IN}	Input Capacitance	5.0			5						pF
C_{OUT}	Output Capacitance	5.0			8						pF
C_{PD}	Power Dissipation Capacitance (note 1)	5.0	$f_{IN} = 10\text{MHz}$		20						pF

1) C_{PD} is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load. (Refer to Test Circuit). Average operating current can be obtained by the following equation. $I_{CC(opr)} = C_{PD} \times V_{CC} \times f_{IN} + I_{CC}/4$ (per circuit)

TEST CIRCUIT



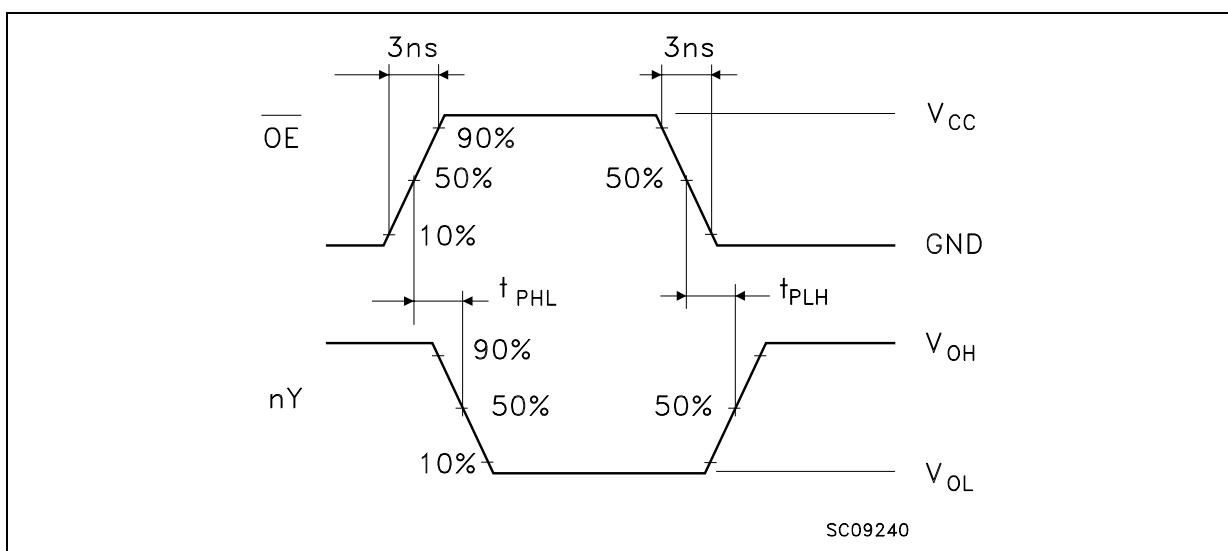
TEST	SWITCH
t_{PLH}, t_{PHL}	Open
t_{PZL}, t_{PLZ}	$2V_{CC}$
t_{PZH}, t_{PHZ}	Open

$C_L = 50\text{pF}$ or equivalent (includes jig and probe capacitance)

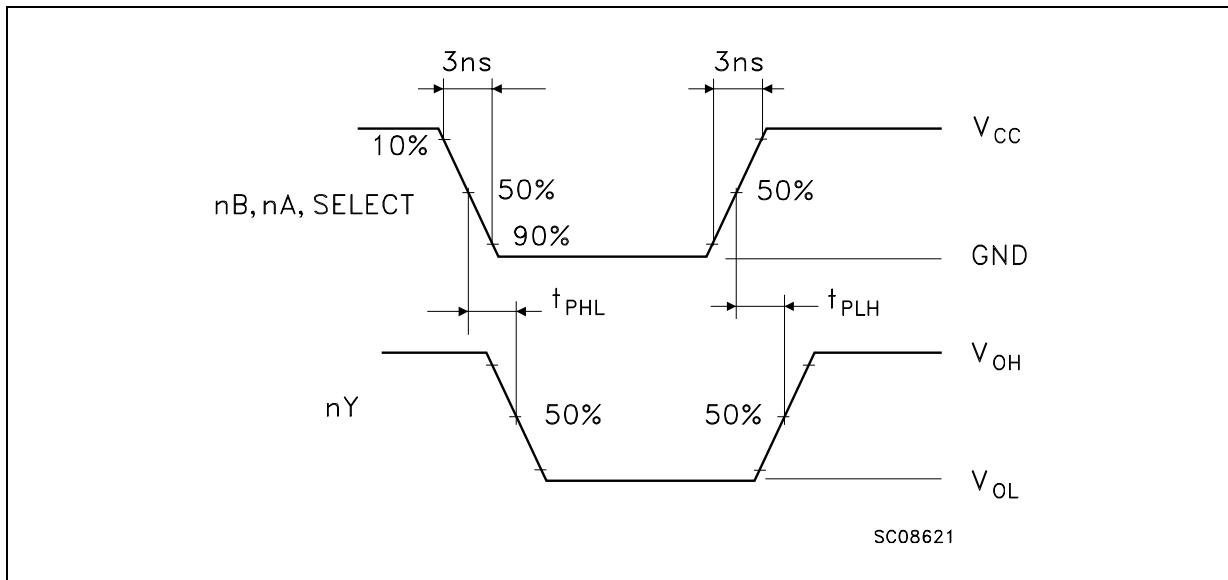
$R_L = R_1 = 500\Omega$ or equivalent

$R_T = Z_{OUT}$ of pulse generator (typically 50Ω)

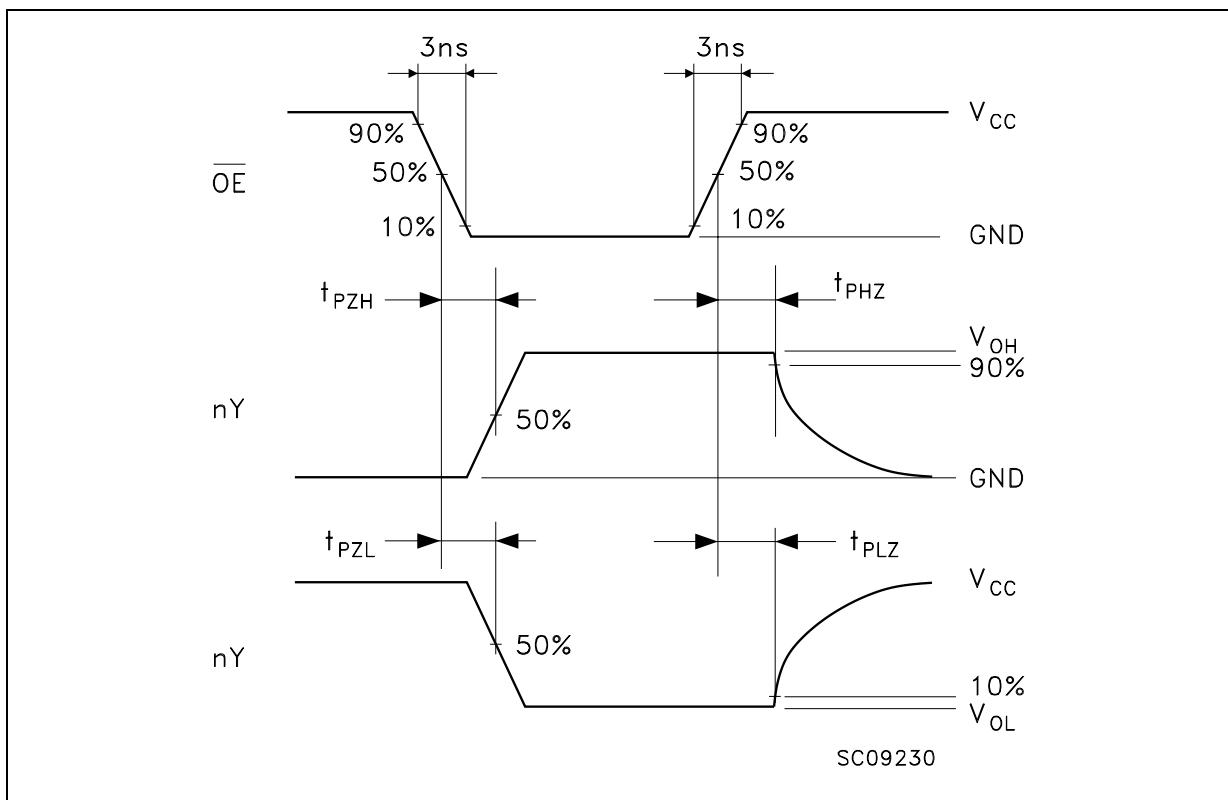
WAVEFORM 1: PROPAGATION DELAYS FOR INVERTING CONDITIONS ($f=1\text{MHz}$; 50% duty cycle)



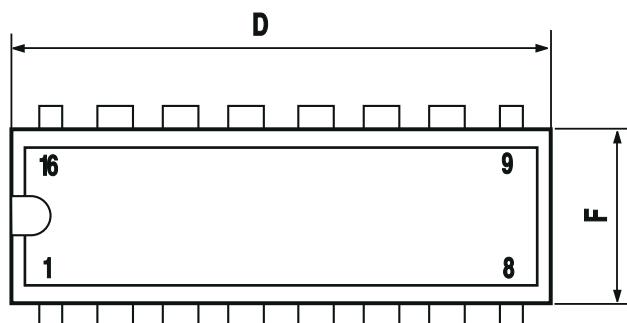
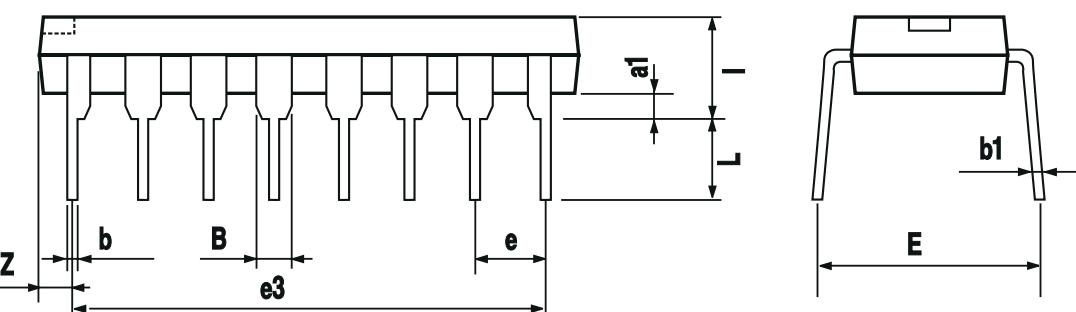
WAVEFORM 2: PROPAGATION DELAYS FOR NON-INVERTING CONDITIONS (f=1MHz; 50% duty cycle)



WAVEFORM 3: OUTPUT ENABLE AND DISABLE TIME (f=1MHz; 50% duty cycle)



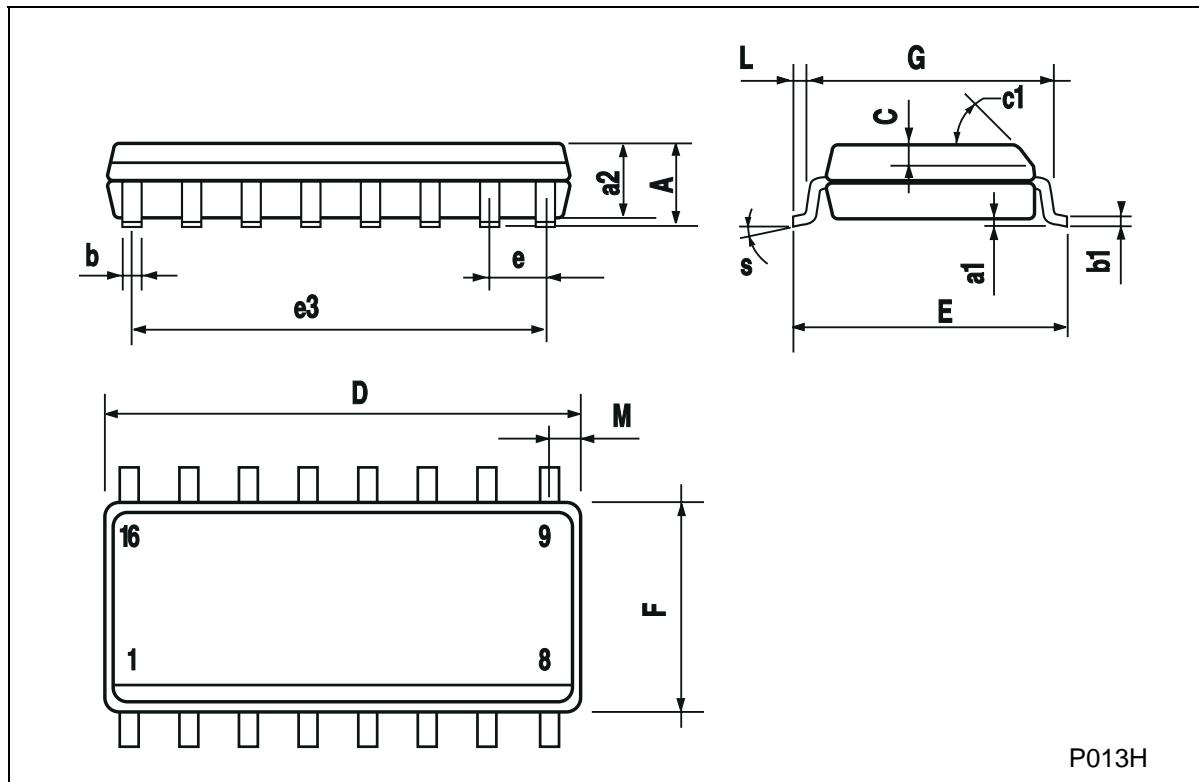
Plastic DIP-16 (0.25) MECHANICAL DATA						
DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
a1	0.51			0.020		
B	0.77		1.65	0.030		0.065
b		0.5			0.020	
b1		0.25			0.010	
D			20			0.787
E		8.5			0.335	
e		2.54			0.100	
e3		17.78			0.700	
F			7.1			0.280
I			5.1			0.201
L		3.3			0.130	
Z			1.27			0.050



P001C

SO-16 MECHANICAL DATA

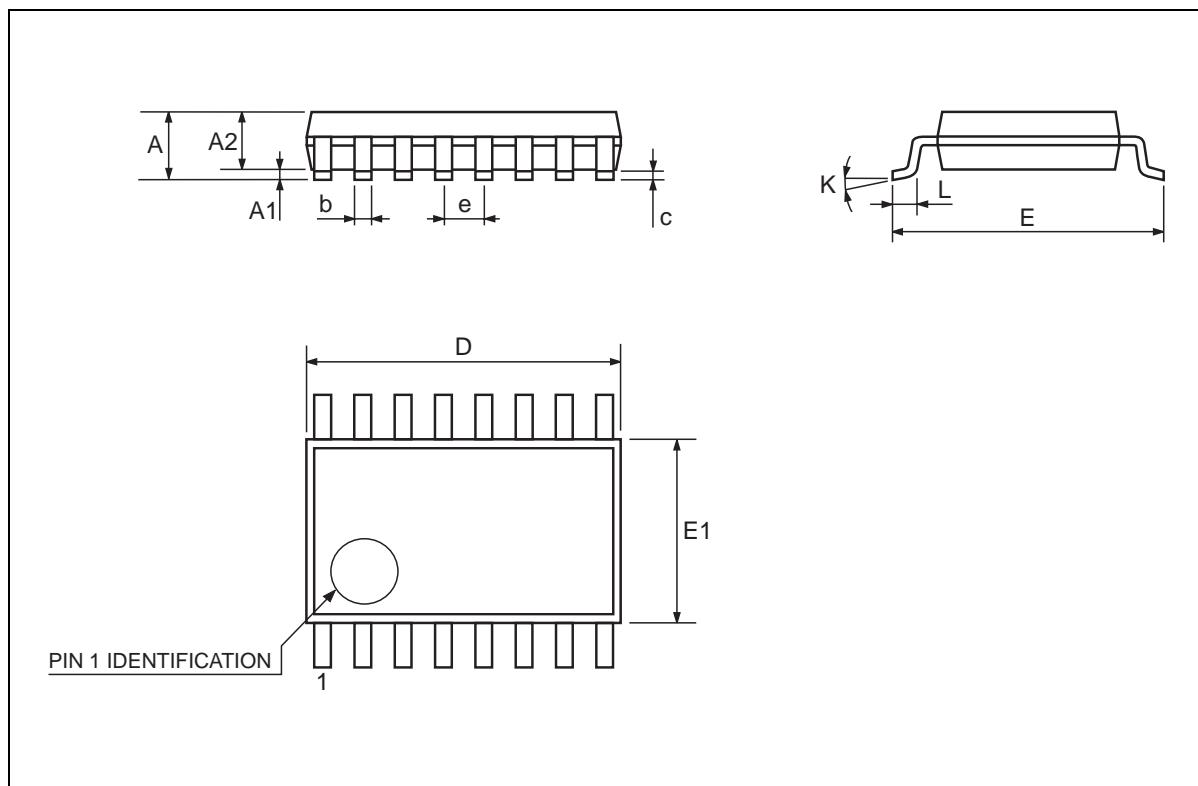
DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.75			0.068
a1	0.1		0.2	0.004		0.007
a2			1.65			0.064
b	0.35		0.46	0.013		0.018
b1	0.19		0.25	0.007		0.010
C		0.5			0.019	
c1		45 (typ.)				
D	9.8		10	0.385		0.393
E	5.8		6.2	0.228		0.244
e		1.27			0.050	
e3		8.89			0.350	
F	3.8		4.0	0.149		0.157
G	4.6		5.3	0.181		0.208
L	0.5		1.27	0.019		0.050
M			0.62			0.024
S		8 (max.)				



P013H

TSSOP16 MECHANICAL DATA

DIM.	mm			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A			1.1			0.433
A1	0.05	0.10	0.15	0.002	0.004	0.006
A2	0.85	0.9	0.95	0.335	0.354	0.374
b	0.19		0.30	0.0075		0.0118
c	0.09		0.20	0.0035		0.0079
D	4.9	5	5.1	0.193	0.197	0.201
E	6.25	6.4	6.5	0.246	0.252	0.256
E1	4.3	4.4	4.48	0.169	0.173	0.176
e		0.65 BSC			0.0256 BSC	
K	0°	4°	8°	0°	4°	8°
L	0.50	0.60	0.70	0.020	0.024	0.028



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